

## 40V N-Channel MOSFET

### General Features

- Proprietary New Trench Technology
- $R_{DS(ON),typ.} = 2.2\text{m}\Omega @ V_{GS} = 10\text{V}$
- Low Gate Charge Minimize Switching Loss
- Fast Recovery Body Diode

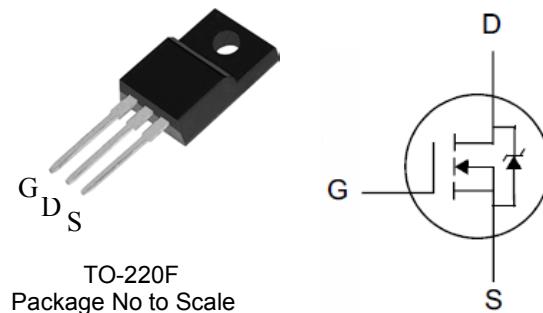
$BV_{DSS}$	$R_{DS(ON),typ.}$	$I_D^{[2]}$
40V	2.2mΩ	240A

### Applications

- High efficiency DC/DC Converters
- Synchronous Rectification
- UPS Inverter

### Ordering Information

Part Number	Package
SK240N04-TF	TO-220F



### Absolute Maximum Ratings

$T_C = 25^\circ\text{C}$  unless otherwise specified

Symbol	Parameter	SK240N04-TF	Unit
$V_{DSS}$	Drain-to-Source Voltage <sup>[1]</sup>	40	V
$V_{GSS}$	Gate-to-Source Voltage	$\pm 20$	
$I_D$	Continuous Drain Current <sup>[2]</sup>	240	A
	Continuous Drain Current <sup>[3]</sup>	80	
$I_{DM}$	Pulsed Drain Current at $V_{GS} = 10\text{V}$ <sup>[2,4]</sup>	960	
$E_{AS}$	Single Pulse Avalanche Energy	1200	mJ
$dv/dt$	Peak Diode Recovery $dv/dt$ <sup>[3]</sup>	5.0	V/ns
$P_D$	Power Dissipation	300	W
	Derating Factor above $25^\circ\text{C}$	2.0	W/ $^\circ\text{C}$
$T_L$ $T_{PAK}$	Maximum Temperature for Soldering Leads at 0.063in (1.6mm) from Case for 10 seconds, Package Body for 10 seconds	300 260	$^\circ\text{C}$
	Operating and Storage Temperature Range	-55 to 150	

Caution: Stresses greater than those listed in the "Absolute Maximum Ratings" may cause permanent damage to the device.

### Thermal Characteristics

Symbol	Parameter	SK240N04-TF	Unit
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	0.5	$^\circ\text{C}/\text{W}$
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	62	

## Electrical Characteristics

### OFF Characteristics $T_J = 25^\circ\text{C}$ unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Unit	Test Conditions
$\text{BV}_{\text{DSS}}$	Drain-to-Source Breakdown Voltage	40	--	--	V	$\text{V}_{\text{GS}}=0\text{V}, \text{I}_D=250\mu\text{A}$
$\text{I}_{\text{DSS}}$	Drain-to-Source Leakage Current	--	--	1	uA	$\text{V}_{\text{DS}}=40\text{V}, \text{V}_{\text{GS}}=0\text{V}$
		--	--	100		$\text{V}_{\text{DS}}=32\text{V}, \text{V}_{\text{GS}}=0\text{V}, T_J = 125^\circ\text{C}$
$\text{I}_{\text{GSS}}$	Gate-to-Source Leakage Current	--	--	+100	nA	$\text{V}_{\text{GS}}=+20\text{V}, \text{V}_{\text{DS}}=0\text{V}$
		--	--	-100		$\text{V}_{\text{GS}}=-20\text{V}, \text{V}_{\text{DS}}=0\text{V}$

### ON Characteristics $T_J = 25^\circ\text{C}$ unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Unit	Test Conditions
$\text{R}_{\text{DS(ON)}}$	Static Drain-to-Source On-Resistance	--	2.2	3.0	$\text{m}\Omega$	$\text{V}_{\text{GS}}=10\text{V}, \text{I}_D=80\text{A}$ [5]
$\text{V}_{\text{GS(TH)}}$	Gate Threshold Voltage	2.0	--	4.0	V	$\text{V}_{\text{DS}}=\text{V}_{\text{GS}}, \text{I}_D=250\mu\text{A}$
$\text{gfs}$	Forward Transconductance	--	221	--	S	$\text{V}_{\text{DS}}=10\text{V}, \text{I}_D=80\text{A}$ [5]

### Dynamic Characteristics

Essentially independent of operating temperature

Symbol	Parameter	Min.	Typ.	Max.	Unit	Test Conditions
$\text{C}_{\text{iss}}$	Input Capacitance	--	4.84	--	nF	$\text{V}_{\text{GS}}=0\text{V}, \text{V}_{\text{DS}}=25\text{V}, f=1.0\text{MHz}$
$\text{C}_{\text{rss}}$	Reverse Transfer Capacitance	--	0.43	--		
$\text{C}_{\text{oss}}$	Output Capacitance	--	0.68	--		
$\text{R}_G$	Gate Series Resistance	--	2.1	--	$\Omega$	$f=1.0\text{MHz}$
$\text{Q}_g$	Total Gate Charge	--	95	--	nC	$\text{V}_{\text{DD}}=20\text{V}, \text{I}_D=80\text{A}, \text{V}_{\text{GS}}=0 \text{ to } 10\text{V}$
$\text{Q}_{\text{gs}}$	Gate-to-Source Charge	--	27	--		
$\text{Q}_{\text{gd}}$	Gate-to-Drain (Miller) Charge	--	28	--		

### Resistive Switching Characteristics

Essentially independent of operating temperature

Symbol	Parameter	Min.	Typ.	Max.	Unit	Test Conditions
$\text{t}_{\text{d(ON)}}$	Turn-on Delay Time	--	21	--	ns	$\text{V}_{\text{DD}}=20\text{V}, \text{I}_D=80\text{A}, \text{V}_{\text{GS}}=10\text{V}, \text{R}_G=2.5\Omega$
$\text{t}_{\text{rise}}$	Rise Time	--	22	--		
$\text{t}_{\text{d(OFF)}}$	Turn-Off Delay Time	--	53	--		
$\text{t}_{\text{fall}}$	Fall Time	--	21	--		

**Source-Drain Body Diode Characteristics**

T<sub>J</sub>=25 °C unless otherwise specified

Symbol	Parameter	Min	Typ.	Max.	Unit	Test Conditions
I <sub>SD</sub>	Continuous Source Current <sup>[2]</sup>	--	--	240	A	Integral PN-diode in MOSFET
I <sub>SM</sub>	Pulsed Source Current <sup>[2]</sup>	--	--	960		
V <sub>SD</sub>	Diode Forward Voltage	--	0.90	1.2	V	I <sub>S</sub> =80A, V <sub>GS</sub> =0V
trr	Reverse recovery time	--	46	--	ns	V <sub>GS</sub> =0V, I <sub>F</sub> =80A, dI <sub>F</sub> /dt=100A/μs
Qrr	Reverse recovery charge	--	19	--	nC	

## Typical Characteristics

**Figure 1. Maximum Effective Thermal Impedance, Junction-to-Case**

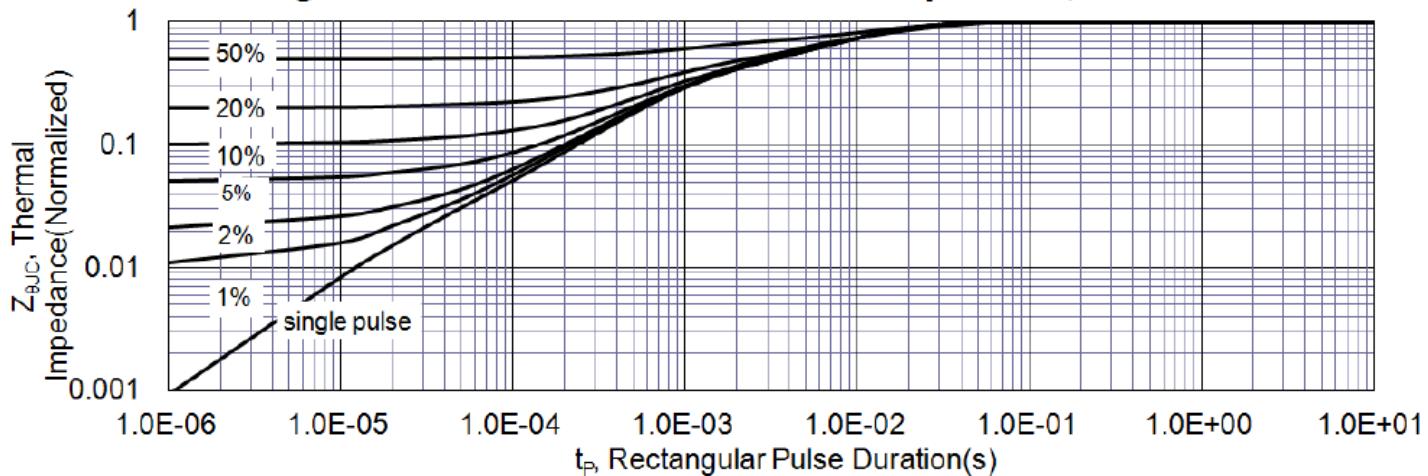


Figure 2. Maximum Power Dissipation vs Case Temperature

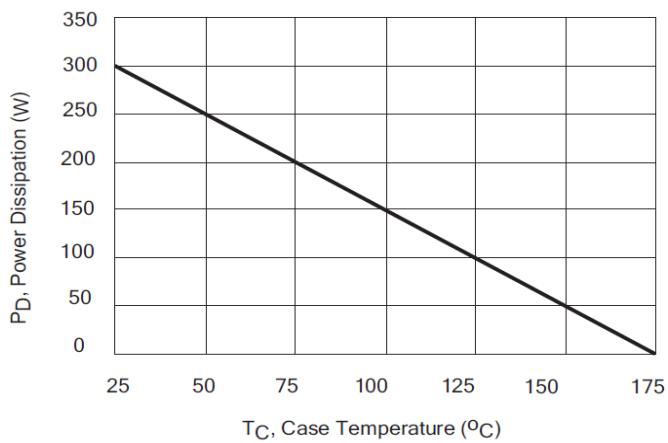


Figure3. Maximum Continuous Drain Current vs Case Temperature

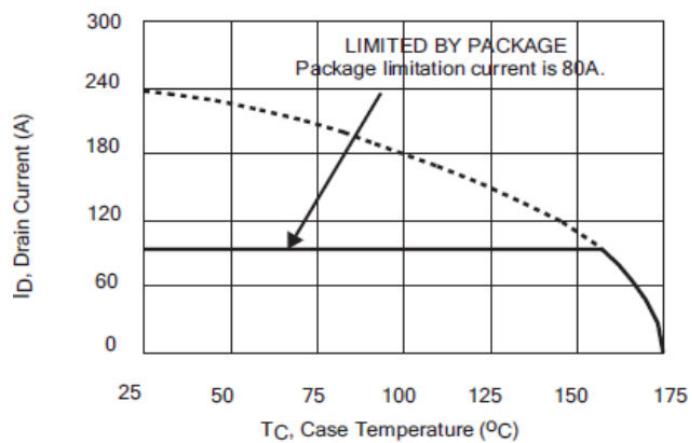


Figure 4. Typical Output Characteristics

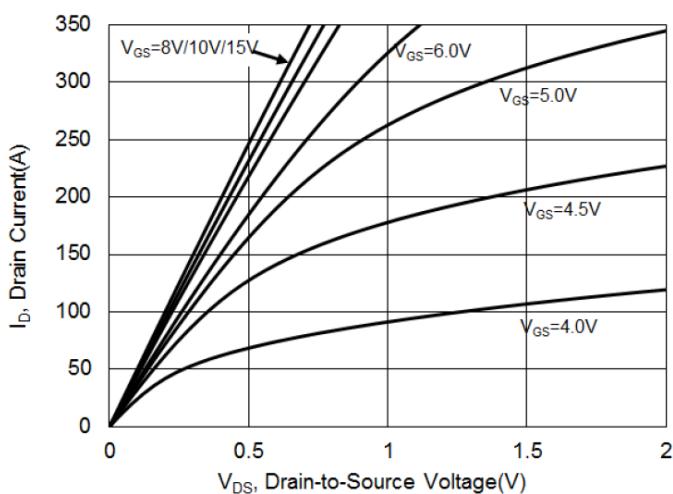
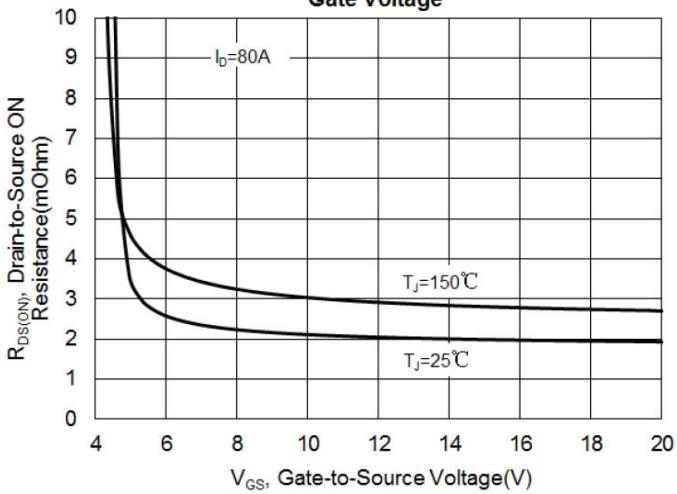
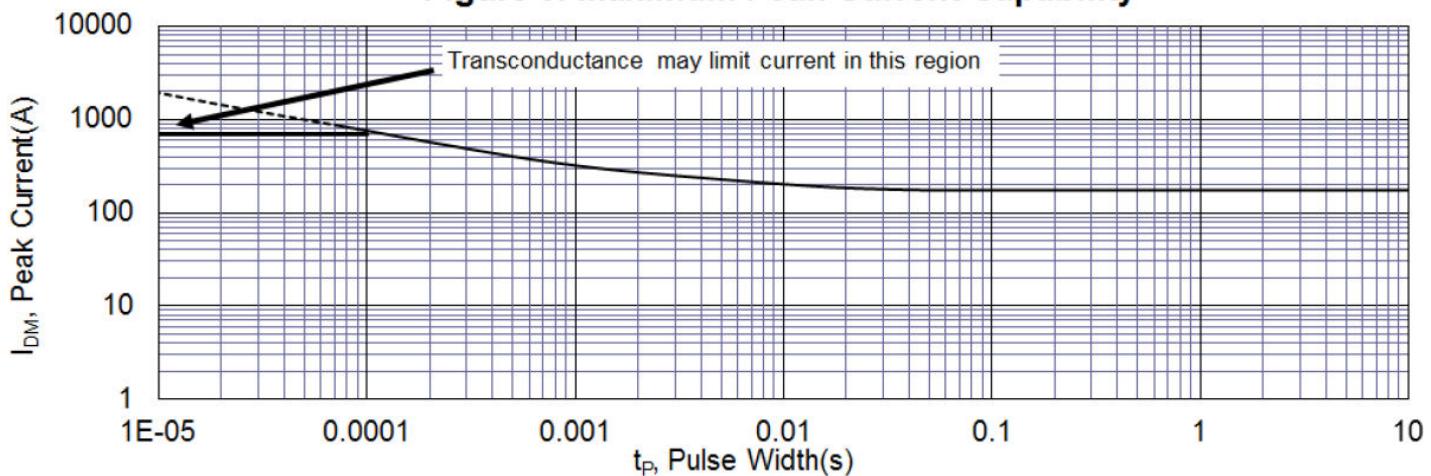


Figure 5. Typical Drain-to-Source ON Resistance vs. Gate Voltage

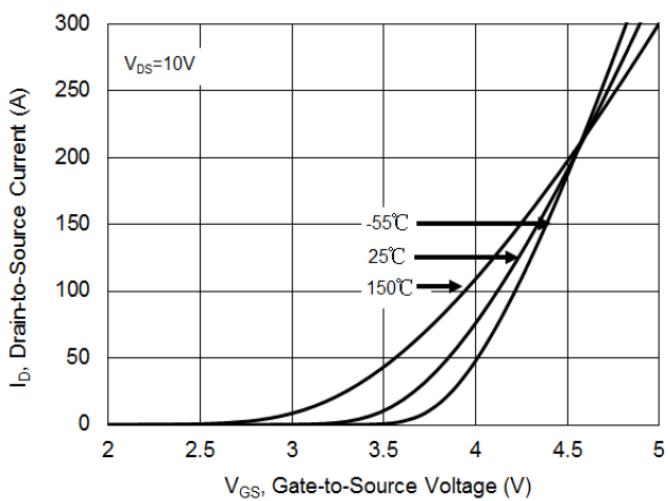


## Typical Characteristics(Cont.)

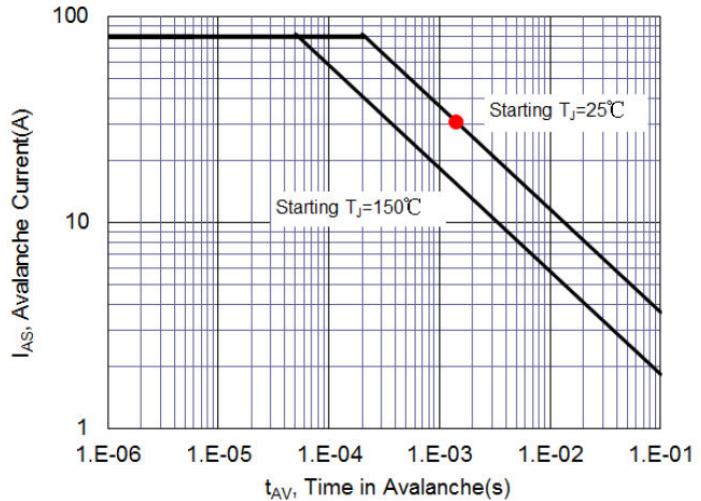
**Figure 6. Maximum Peak Current Capability**



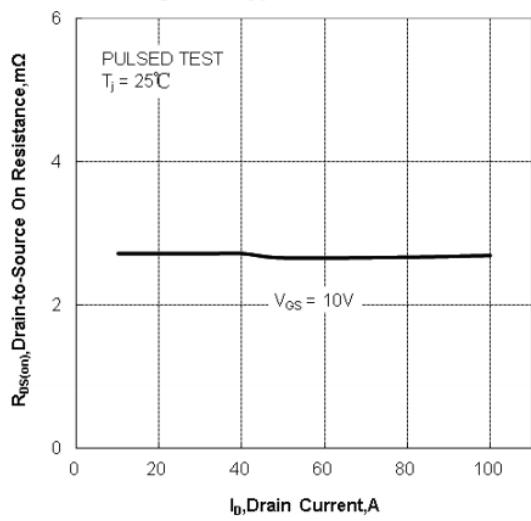
**Figure 7. Typical Transfer Characteristics**



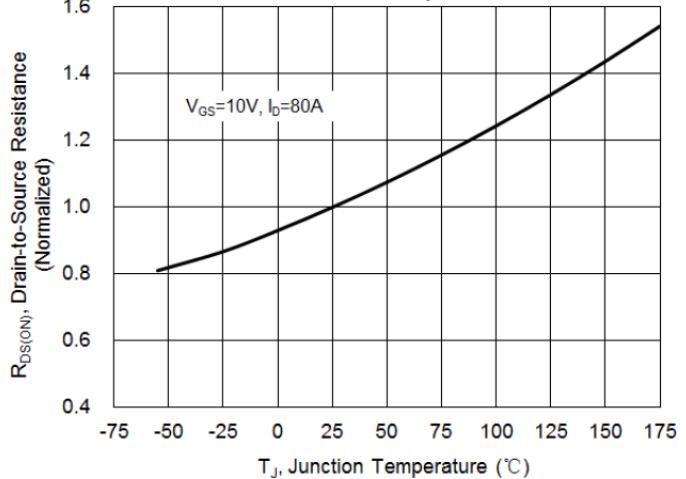
**Figure 8. Unclamped Inductive Switching Capability**



**Figure 9. Typical Drain-to-Source ON Resistance**



**Figure 10. Typical Drain-to-Source On Resistance vs. Junction Temperature**



## Typical Characteristics(Cont.)

Figure 11. Typical Breakdown Voltage vs. Junction Temperature

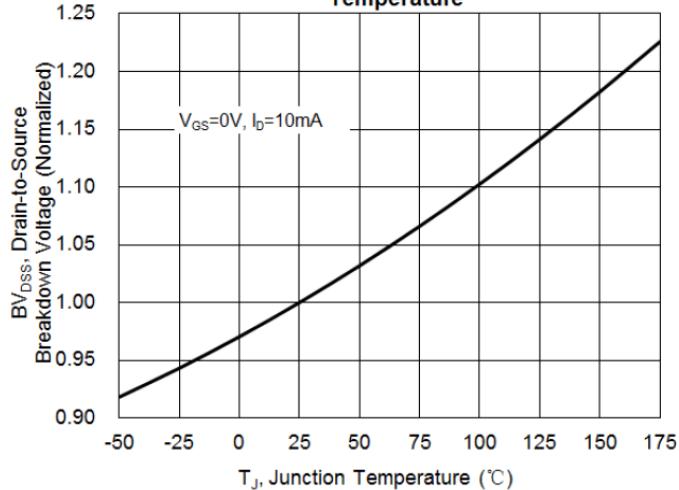


Figure 13. Maximum Forward Safe Operation Area

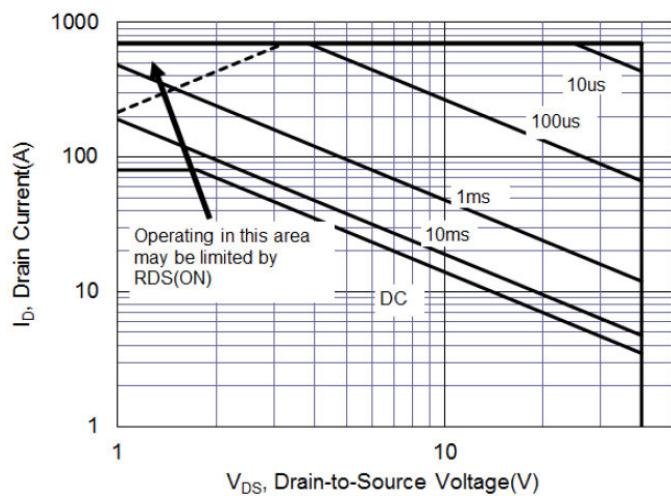


Figure 15. Typical Gate Charge vs. Gate-to-Source Voltage

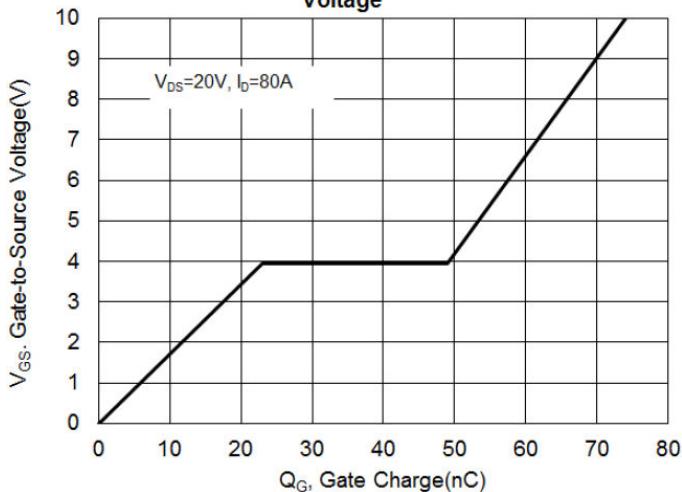


Figure 12. Typical Threshold Voltage vs. Junction Temperature

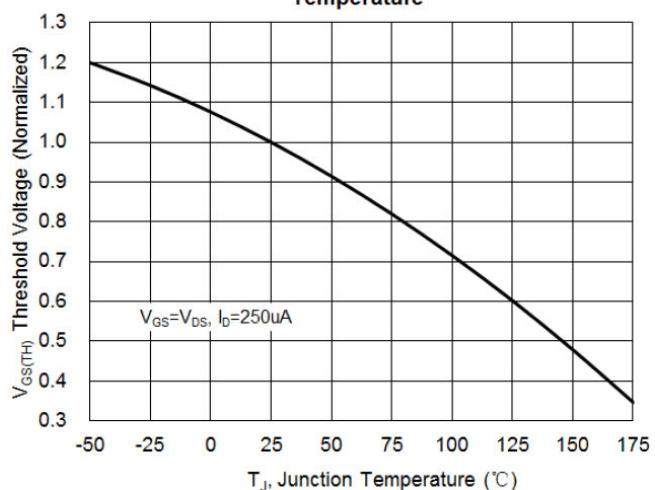


Figure 14. Typical Capacitance vs. Drain-to-Source Voltage

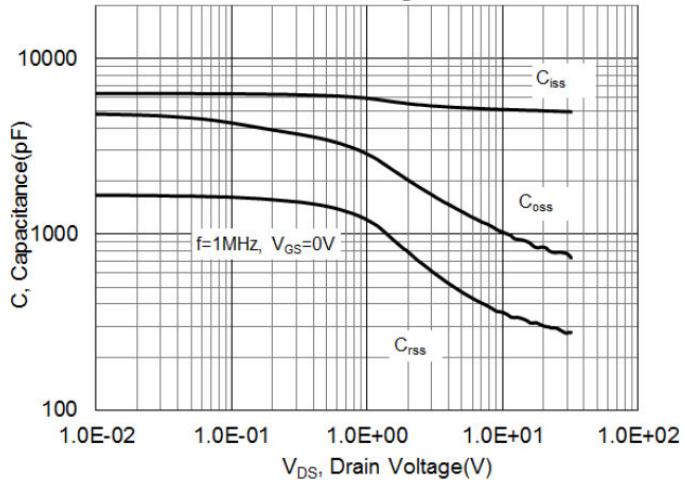
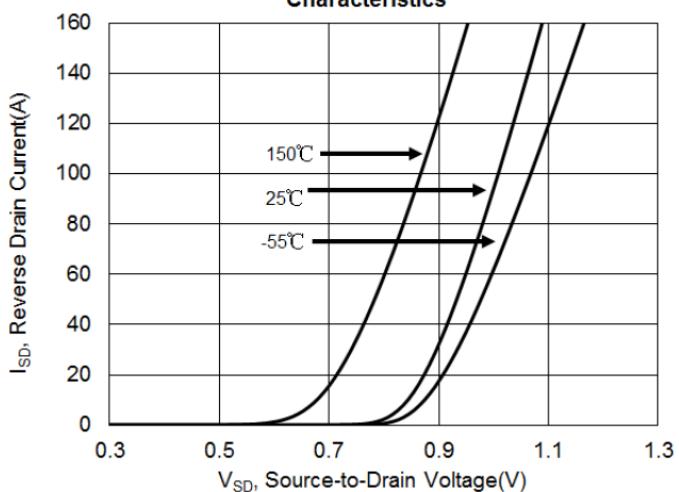


Figure 16. Typical Body Diode Transfer Characteristics



## Test Circuits and Waveforms

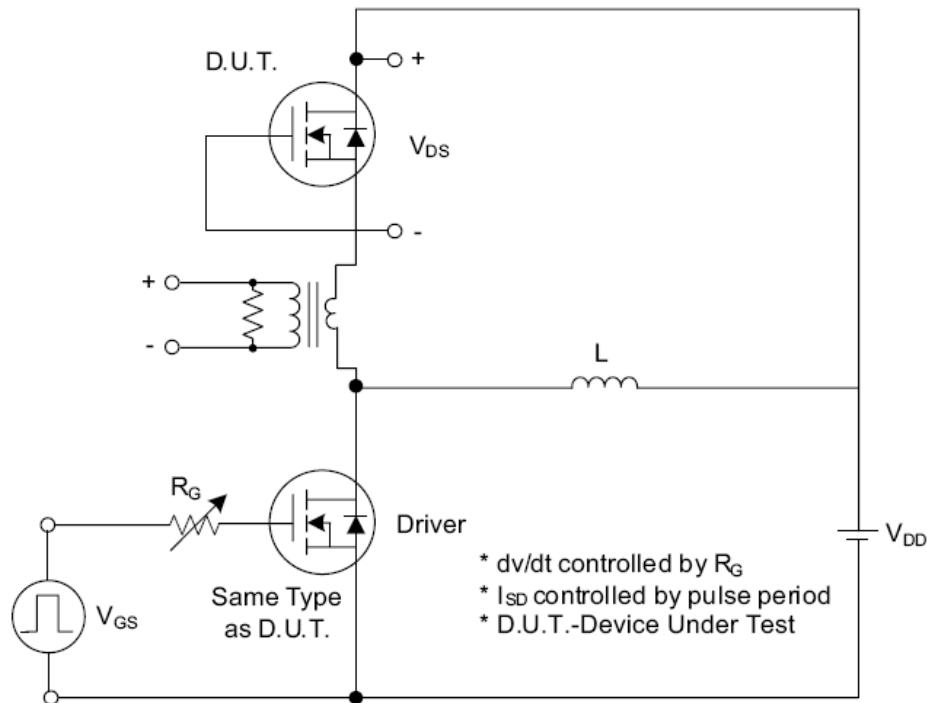


Fig. 1.1 Peak Diode Recovery  $dV/dt$  Test Circuit

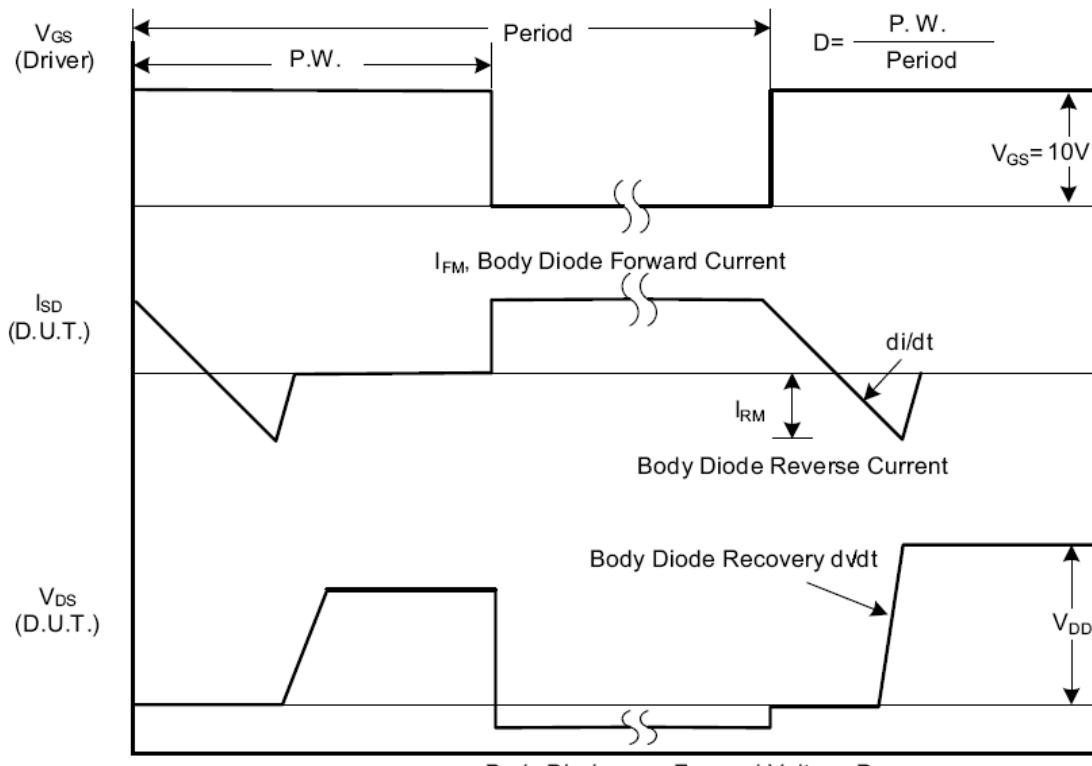


Fig. 1.2 Peak Diode Recovery  $dV/dt$  Waveforms

## Test Circuits and Waveforms (Cont.)

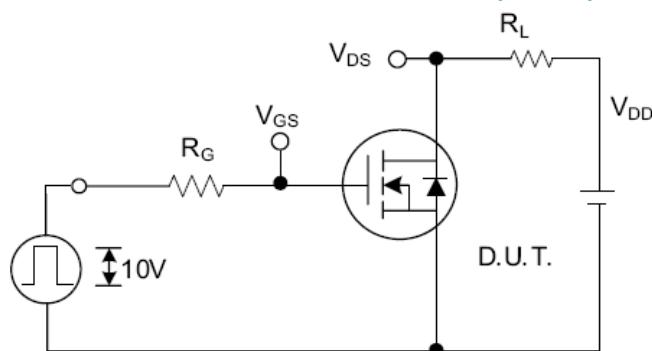


Fig. 2.1 Switching Test Circuit

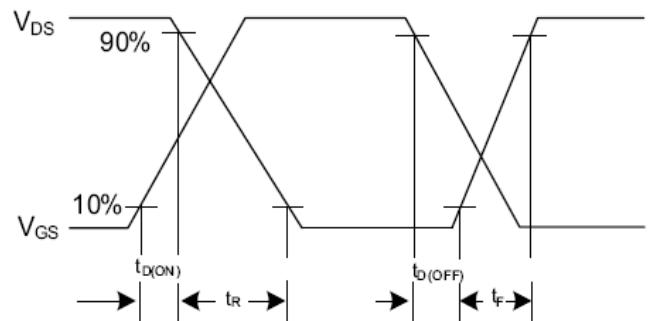


Fig. 2.2 Switching Waveforms

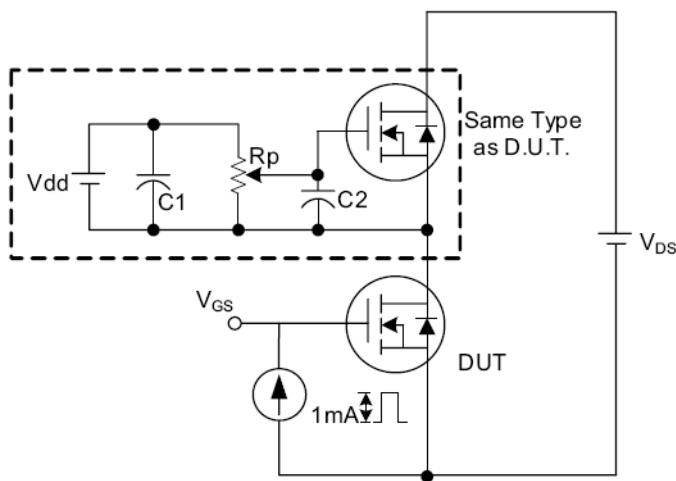


Fig. 3 . 1 Gate Charge Test Circuit

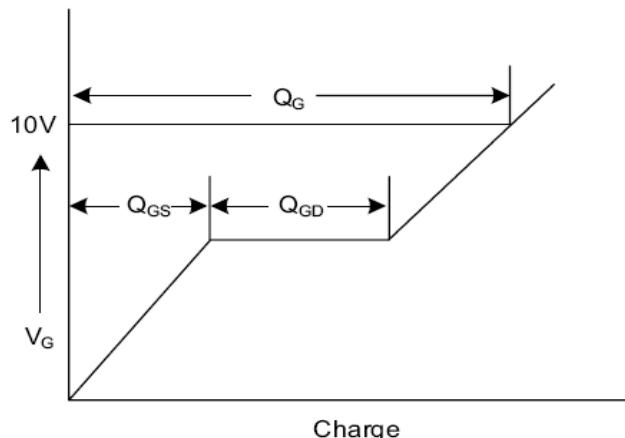


Fig. 3 . 2 Gate Charge Waveform

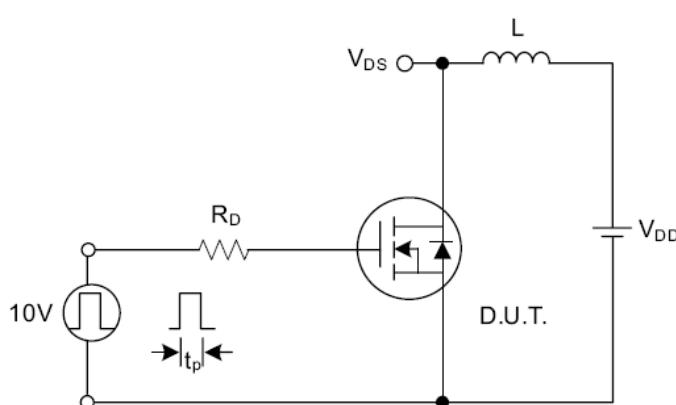


Fig. 4.1 Unclamped Inductive Switching Test Circuit

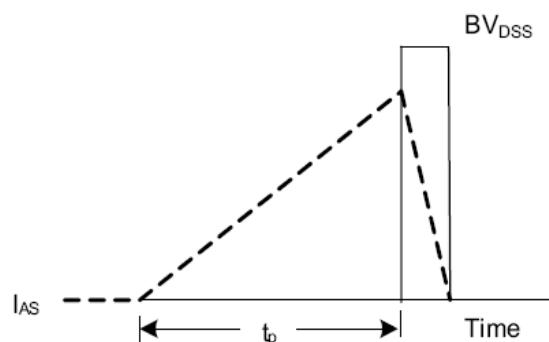


Fig. 4.2 Unclamped Inductive Switching Waveforms

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